

Zinc oxide nanocrystals as electron injecting building blocks for plastic light sources

Supporting Information

Michele Sessolo,^a Henk J. Bolink,^{*ab} Hicham Brine^a, Helena Prima-Garcia^a and Ramon Tena-Zaera^{*c}

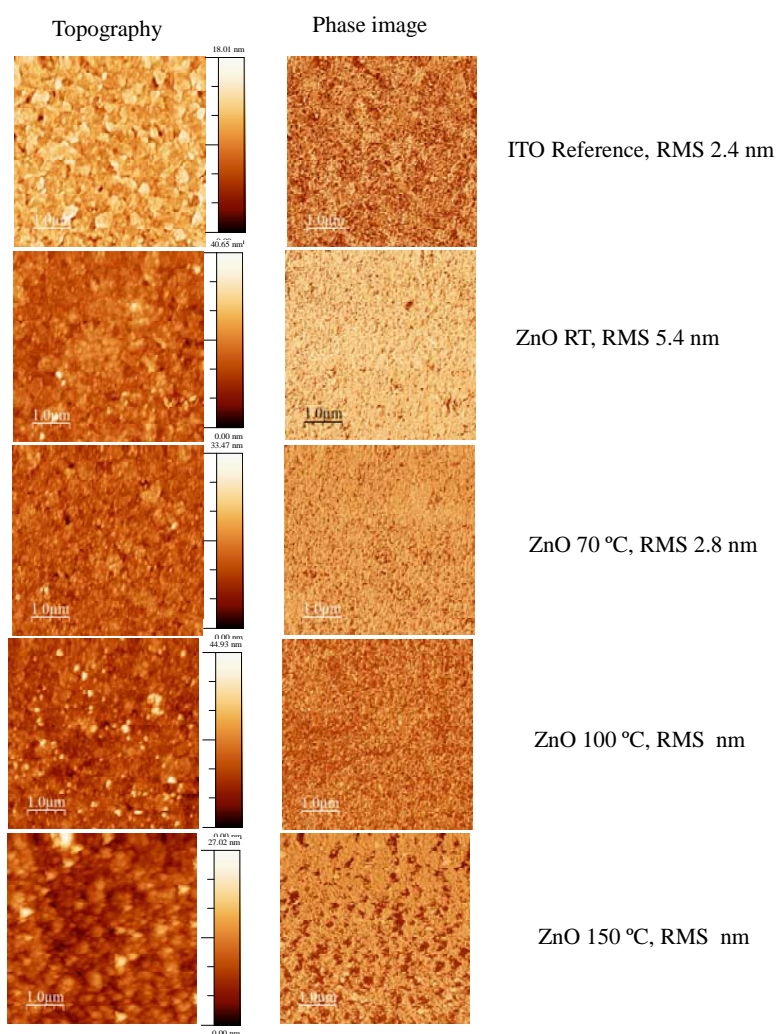


Fig. S1 AFM topographies (left) and corresponding phase images (right) registered for the ITO substrate and the ZnO NCs layers annealed at different temperatures.

^aInstituto de Ciencia Molecular, Universidad de València
PO Box 22085, ES-46071 Valencia, Spain. Email: henk.bolink@uv.es

^bFundació General de la Universitat de València (FGUV)
PO Box 22085, ES-46071 Valencia, Spain.

^cEnergy Department, CIDETEC-IK4
Parque Tecnológico de San Sebastián, Paseo Miramón 196
Donostia-San Sebastián, 20009, Spain. Email: rtena@cidetec.es

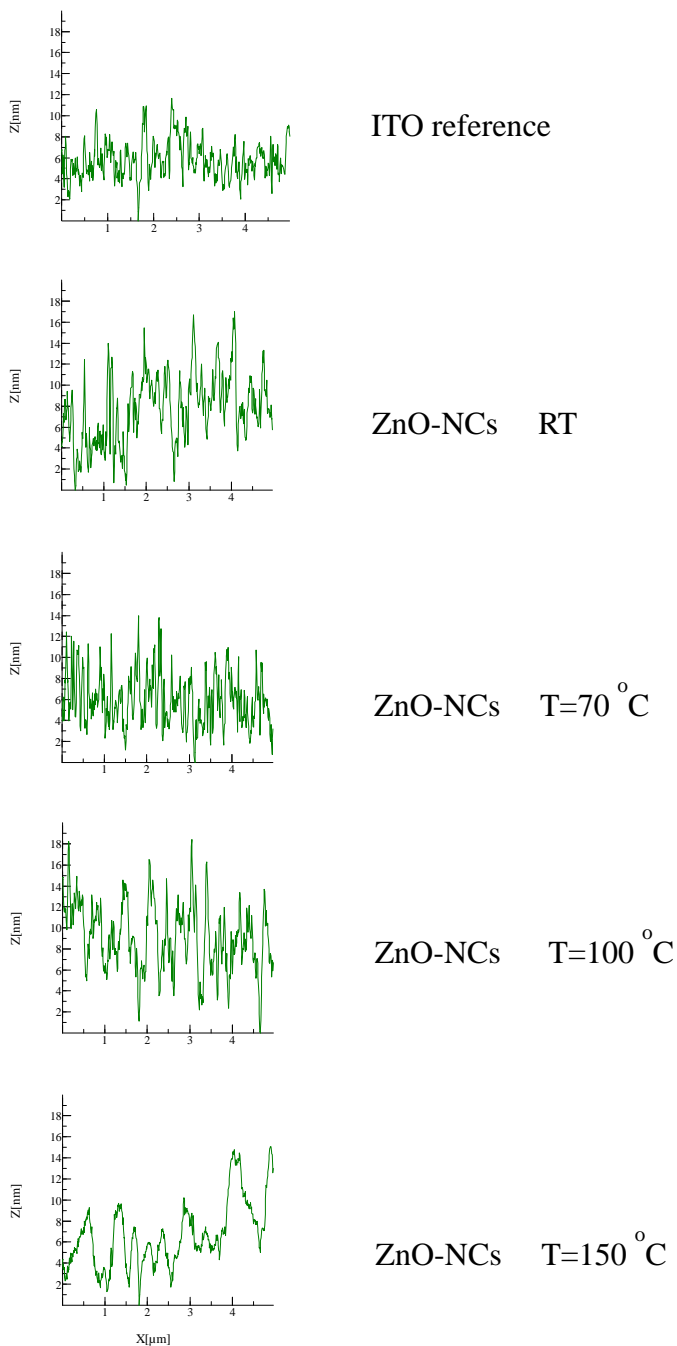


Fig. S2. Topology profile (peak to valley) of the AFM images presented in Fig. S1.

To complete the HRTEM images below the image obtained for samples annealed at 100°C is depicted. The images for room temperature and 150°C are displayed in the manuscript (Fig. 1 and 3, respectively).

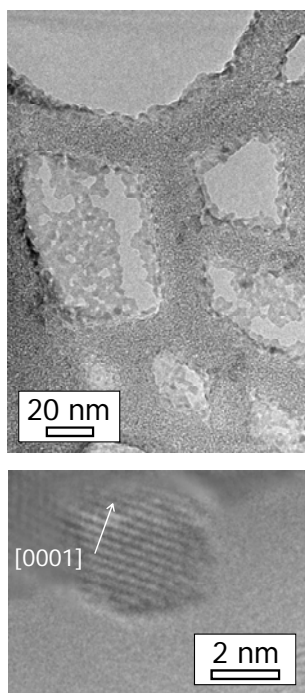


Fig. S3. HRTEM image of the ZnO NCs annealed at 100 °C, with a higher magnification image of a single ZnO NC.

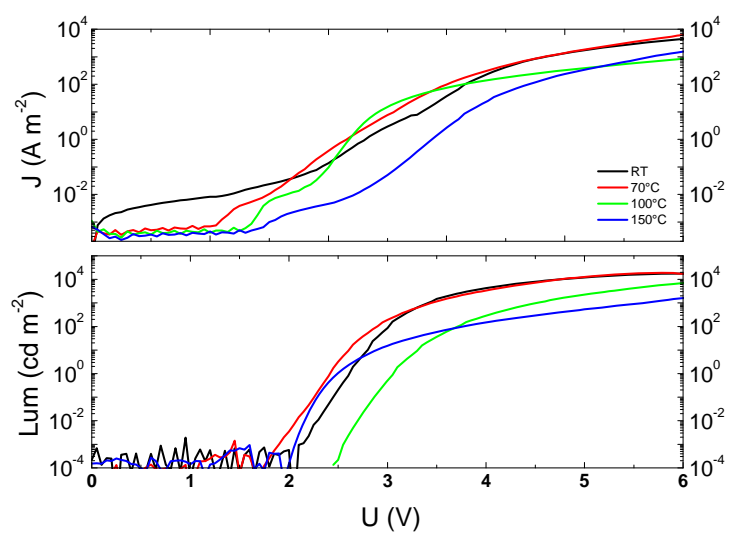


Fig. S4. Current density and luminance for a series of HyLEDs employing ZnO NCs layers treated at different temperatures